

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π -MOSV)

2SK2995

Chopper Regulator, DC-DC Converter and Motor Drive Applications

- Low drain-source ON resistance : $R_{DS(ON)} = 48 \text{ m}\Omega$ (typ.)
- High forward transfer admittance : $|Y_{fs}| = 30 \text{ S}$ (typ.)
- Low leakage current : $I_{DSS} = 100 \text{ }\mu\text{A}$ (max) ($V_{DS} = 250 \text{ V}$)
- Enhancement mode : $V_{th} = 1.5\sim 3.5 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	250	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	250	V
Gate-source voltage		V_{GSS}	± 20	V
Drain current	DC (Note 1)	I_D	30	A
	Pulse (Note 1)	I_{DP}	120	A
Drain power dissipation ($T_c = 25^\circ\text{C}$)		P_D	90	W
Single pulse avalanche energy (Note 2)		E_{AS}	925	mJ
Avalanche current		I_{AR}	30	A
Repetitive avalanche energy (Note 3)		E_{AR}	9	mJ
Channel temperature		T_{ch}	150	$^\circ\text{C}$
Storage temperature range		T_{stg}	-55~150	$^\circ\text{C}$

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th(ch-c)}$	1.39	$^\circ\text{C} / \text{W}$
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	41.6	$^\circ\text{C} / \text{W}$

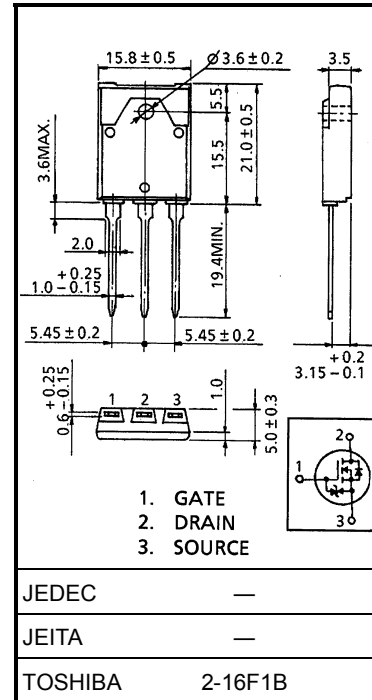
Note 1: Ensure that the channel temperature does not exceed 150°C .

Note 2: $V_{DD} = 50 \text{ V}$, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 1.74 \text{ mH}$, $I_{AR} = 30 \text{ A}$, $R_G = 25 \text{ }\Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature.

This transistor is an electrostatic-sensitive device.
Please handle with caution.

Unit: mm



Weight: 1.9 g (typ.)

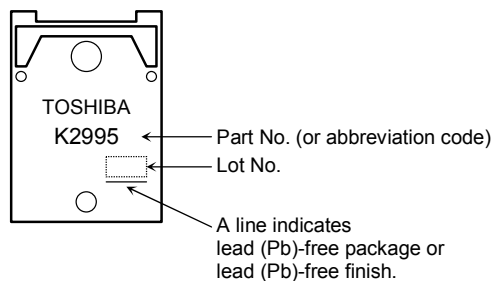
Electrical Characteristics (Ta = 25°C)

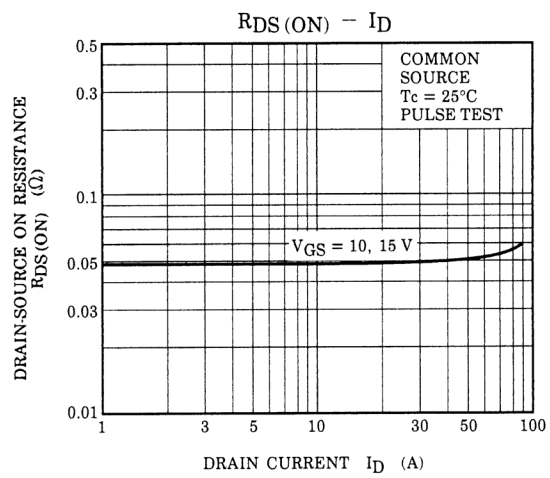
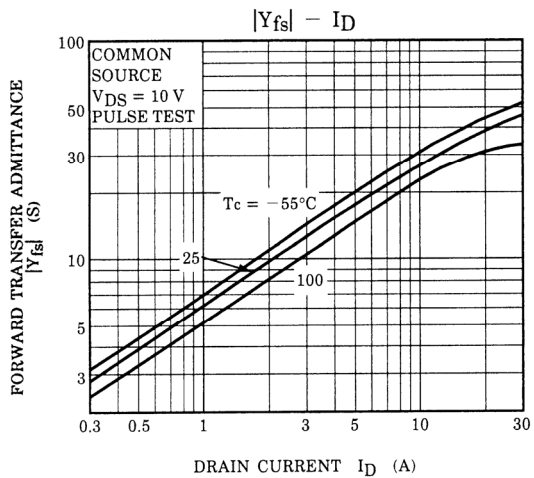
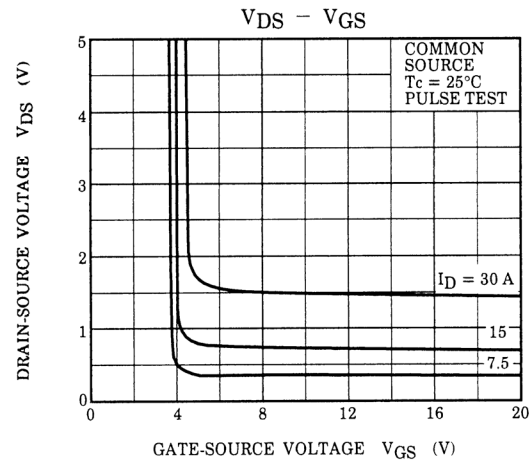
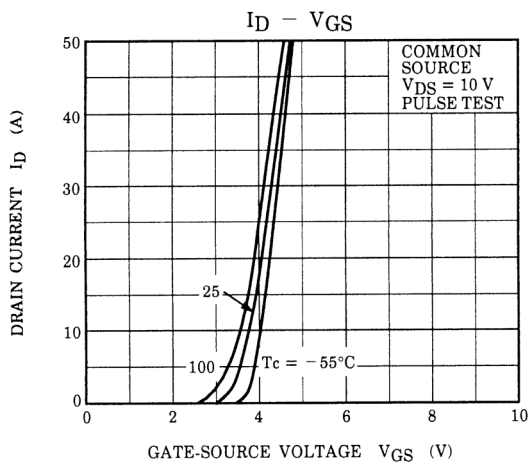
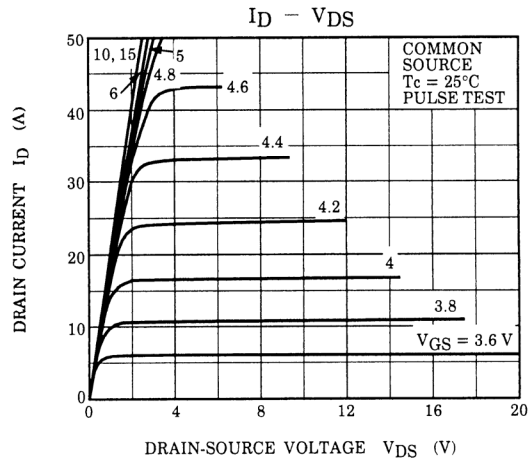
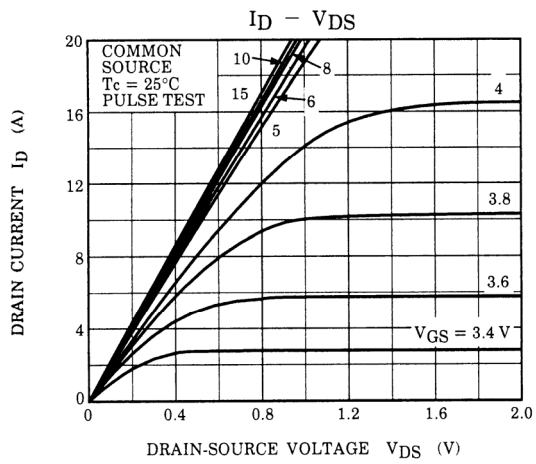
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 16\text{ V}, V_{DS} = 0\text{ V}$	—	—	± 10	μA
Drain cut-off current		I_{DSS}	$V_{DS} = 250\text{ V}, V_{GS} = 0\text{ V}$	—	—	100	μA
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = 10\text{ mA}, V_{GS} = 0\text{ V}$	250	—	—	V
Gate threshold voltage		V_{th}	$V_{DS} = 10\text{ V}, I_D = 1\text{ mA}$	1.5	—	3.5	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 10\text{ V}, I_D = 15\text{ A}$	—	48	68	m Ω
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10\text{ V}, I_D = 15\text{ A}$	15	30	—	S
Input capacitance		C_{iss}	$V_{DS} = 10\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$	—	5400	—	pF
Reverse transfer capacitance		C_{rss}		—	580	—	
Output capacitance		C_{oss}		—	1900	—	
Switching time	Rise time	t_r	<p>Duty $\leq 1\%$, $t_w = 10\mu\text{s}$</p>	—	20	—	ns
	Turn-on time	t_{on}		—	50	—	
	Fall time	t_f		—	35	—	
	Turn-off time	t_{off}		—	200	—	
Total gate charge (gate-source plus gate-drain)		Q_g	$V_{DD} \approx 200\text{ V}, V_{GS} = 10\text{ V}, I_D = 30\text{ A}$	—	132	—	nC
Gate-source charge		Q_{gs}		—	80	—	
Gate-drain ("miller") charge		Q_{gd}		—	52	—	

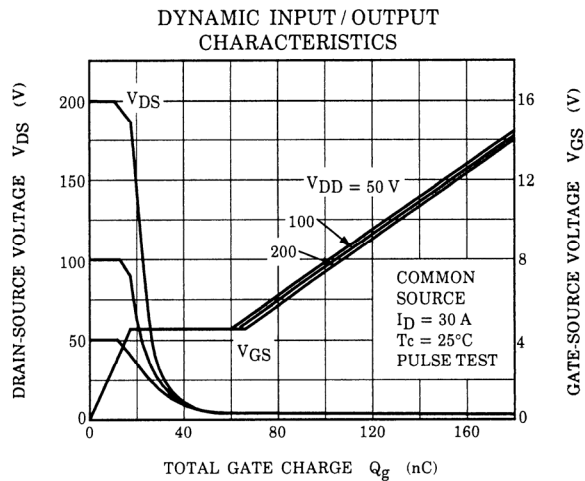
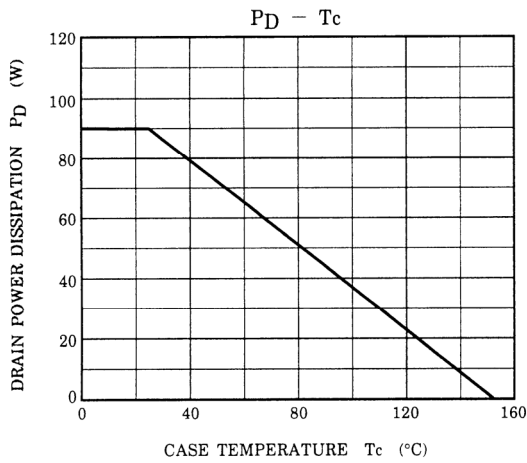
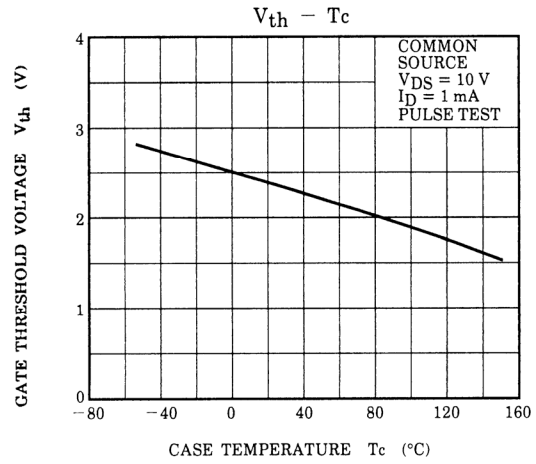
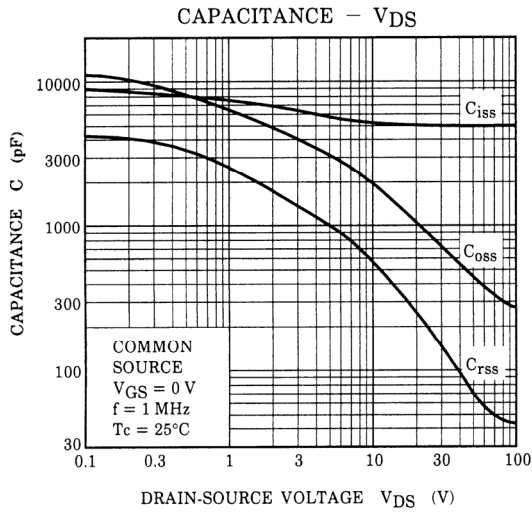
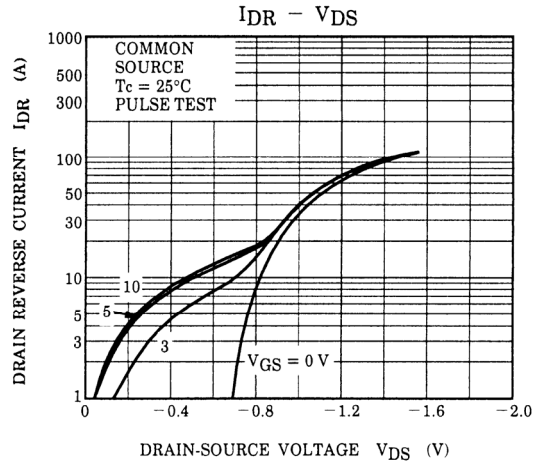
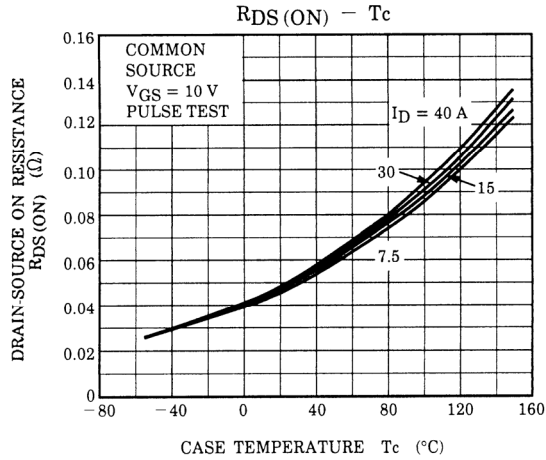
Source-Drain Ratings and Characteristics (Ta = 25°C)

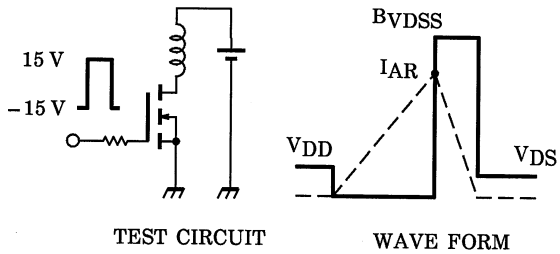
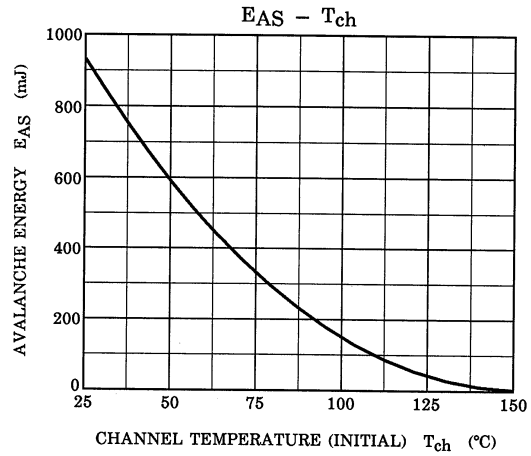
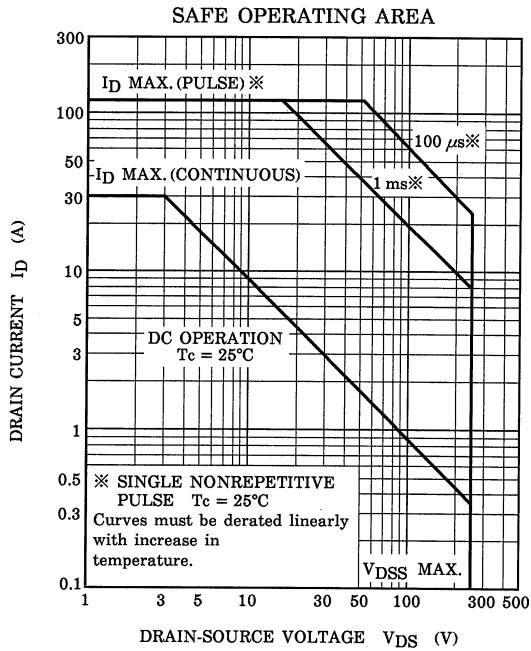
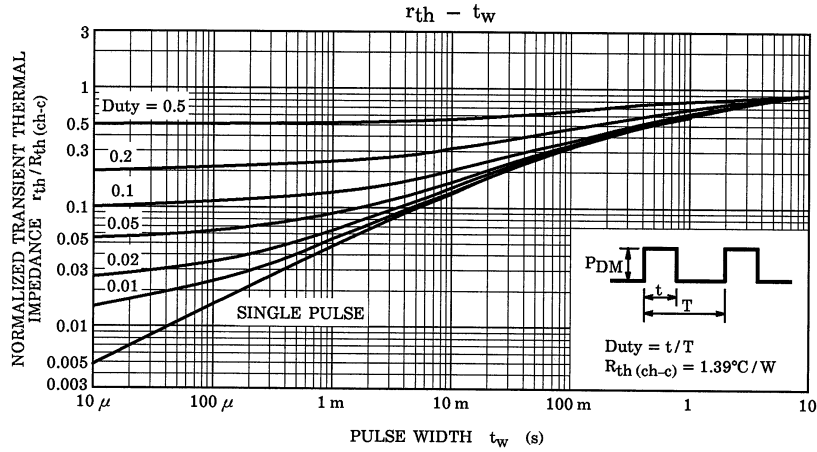
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)		I_{DR}	—	—	—	30	A
Pulse drain reverse current (Note 1)		I_{DRP}	—	—	—	120	A
Forward voltage (diode)		V_{DSF}	$I_{DR} = 30\text{ A}, V_{GS} = 0\text{ V}$	—	—	-2.0	V
Reverse recovery time		t_{rr}	$I_{DR} = 30\text{ A}, V_{GS} = 0\text{ V}$	—	270	—	ns
Reverse recovery charge		Q_{rr}	$dI_{DR} / dt = 100\text{ A} / \mu\text{s}$	—	3.0	—	μC

Marking









$R_G = 25 \Omega$
 $V_{DD} = 50 \text{ V}, L = 1.74 \text{ mH}$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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